

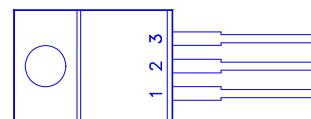
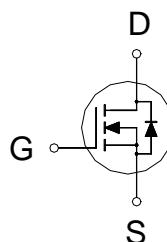
**NIKO-SEM****N-Channel Logic Level Enhancement  
Mode Field Effect Transistor****P1606BT**

TO-220

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
60V	18.5mΩ	42A


 1.GATE  
2.DRAIN  
3.SOURCE
**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>2</sup>	$T_C = 25^\circ C$	$I_D$	42	A
	$T_C = 100^\circ C$		26	
Pulsed Drain Current <sup>1,2</sup>		$I_{DM}$	110	
Avalanche Current		$I_{AS}$	42	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	88	mJ
Power Dissipation	$T_C = 25^\circ C$	$P_D$	62.5	W
	$T_C = 100^\circ C$		25	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2	°C / W
Junction-to-Ambient	$R_{\theta JA}$		75	°C / W

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Limited only by maximum temperature allowed.**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ C$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	60			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.5	3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 48V, V_{GS} = 0V$			1	$\mu A$
		$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ C$			10	
On-State Drain Current <sup>1</sup>	$I_{D(ON)}$	$V_{DS} = 5V, V_{GS} = 10V$	110			A

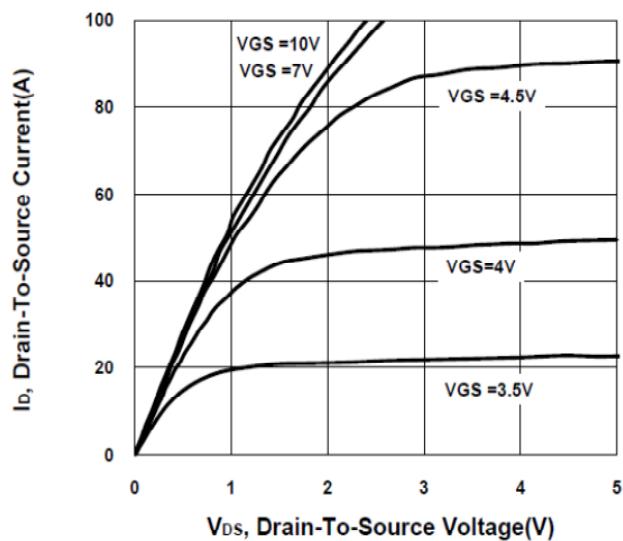
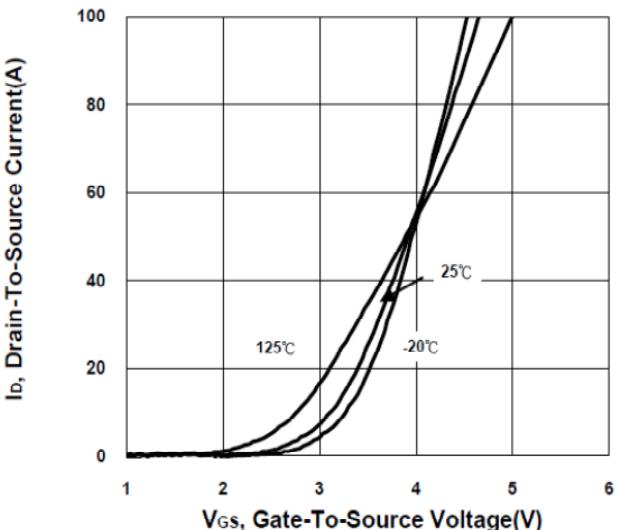
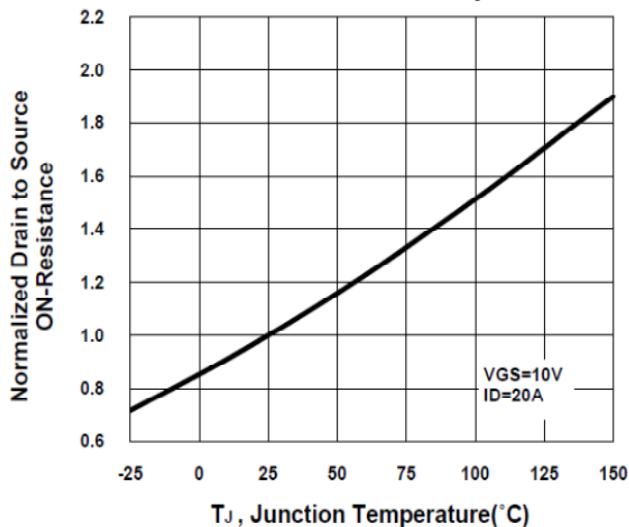
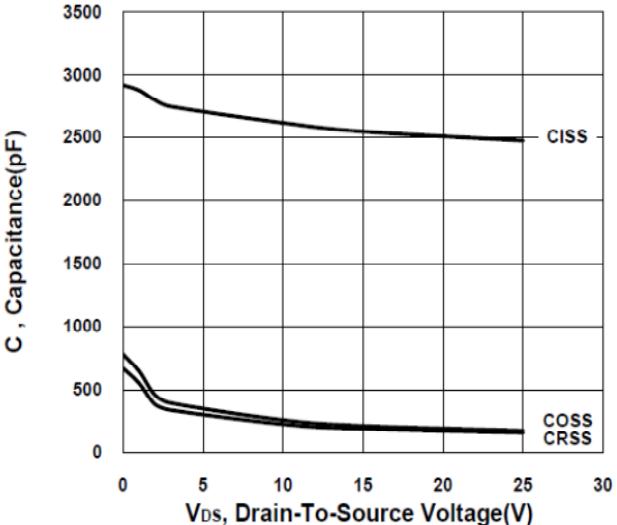
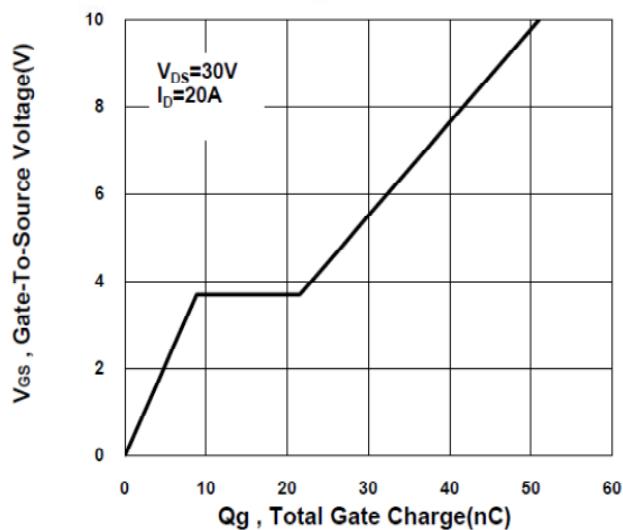
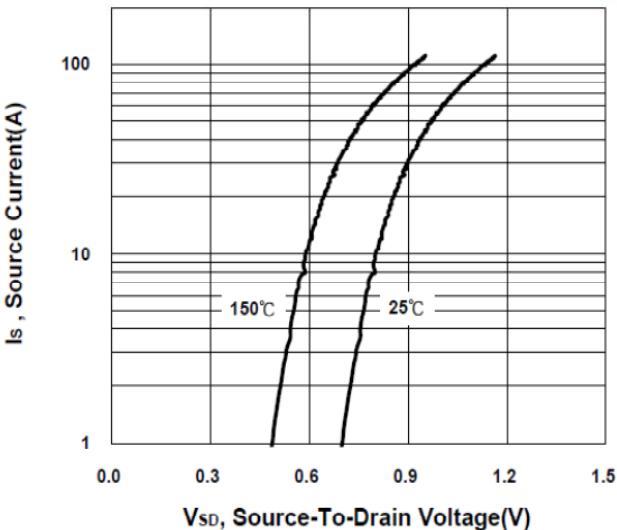
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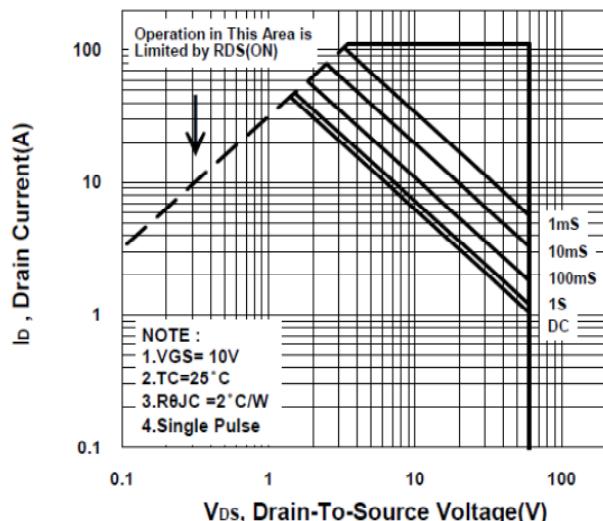
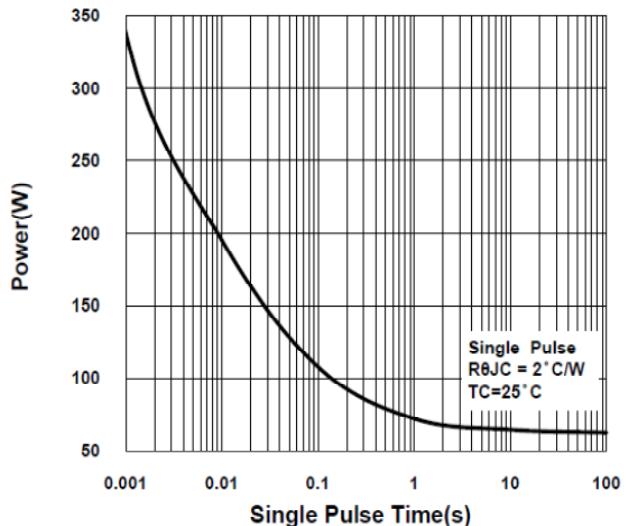
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Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 20A$	17	21	$m\Omega$
		$V_{GS} = 10V, I_D = 20A$	13	18.5	$m\Omega$
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 10V, I_D = 20A$	45		S
<b>DYNAMIC</b>					
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	2710		
Output Capacitance	$C_{oss}$		178		pF
Reverse Transfer Capacitance	$C_{rss}$		136		
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	2		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DS} = 30V, V_{GS} = 10V, I_D = 20A$	55		
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		9.9		nC
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		12.5		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = 30V$ $I_D \geq 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$	20		
Rise Time <sup>2</sup>	$t_r$		70		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		50		nS
Fall Time <sup>2</sup>	$t_f$		25		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>					
Continuous Current	$I_S$	$I_F = 20A, V_{GS} = 0V$ $I_F = 20A, dI_F/dt = 100A / \mu S$		42	A
Forward Voltage <sup>1</sup>	$V_{SD}$			1.3	V
Reverse Recovery Time	$t_{rr}$		32		ns
Reverse Recovery Charge	$Q_{rr}$		35		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

**NIKO-SEM****N-Channel Logic Level Enhancement  
Mode Field Effect Transistor****P1606BT  
TO-220****Halogen-Free & Lead-Free****Output Characteristics****Transfer Characteristics****On-Resistance VS Temperature****Capacitance Characteristic****Gate charge Characteristics****Source-Drain Diode Forward Voltage**

**Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**